

Name	Dr. Ohileshwari MS		
Date of Birth	20/05/1979		
Address	Contact Address:Dr. Ohileshwari MS, Asst Professor, Department of ECE, RNSIT, Bangalore-98 E-mail: ohileshwarims@gmail.com		
Subject / Discipline/ Major	Electronics and Communication Engineering		
Educational Qualifications	Exam Passed	Institution University	Year
	Degree: BE(ECE)	KVG College of Engineering/Mangaluru	2001
	PG: M.Tech(VLSI and Embedded system)	BMS College of Engineering/VTU	2009
	Ph.D : VLSI Testing	GAT, Bengaluru/VTU	2020
Experience	Nature of Experience	No. of Years	
	Teaching	20	
	Industry/Research	-	
	Total No. of years of Experience	20	
Experience Details	Designation	Institution/ Organization	Duration
	Assistant professor	RNS Institute of Technology	Jan 2011 – till date
	Assistant professor	BNMIT, Bangalore	Dec 2005 – Jan 2011
	Lecturer	CIT, Ponnampet	Aug 2001- July 2002
	Lecturer	KVGCE, Sullia	Sep 2002 Aug 2004
	Lecturer	CEC, Bantwal	Aug 2004-Sep 2005
Professional bodies Membership details	IEEE		
Other Professional Experiences			
Areas of Research Interest & Guidance	VLSI testing		
National/ International Work Shops/ Seminars / Conferences Attended	<ul style="list-style-type: none"> • Hardware Modelling Using HDL ATAL FDP on “Recent Trends in the world of Photonics” from 26th July to 30th July 2021(5 Days) at RNSIT, Bengaluru. • 5 days FDP on Hardware Modelling Using HDL at BNMIT from Jan20th – Jan24,2020 • 2 days workshop on Embedded System with ARM From Aug 2 to Aug 3rd 2019 • 5 days workshop on Helping our students through the college years at GAT, Bangalore feom 21st Jan 2019 to 25th Jan 2019 • 3 days FDP on “<i>Python programming and applications</i>” from 18 – 20, June 2018 at RNSIT, Bengaluru. • IEEE sponsored 3-day workshop on “<i>Computer Networks Laboratory using NS3, NCTUNS and C/C++</i>” during January 23-25, 2018 at RNSIT, Bengaluru. • FDP on “<i>Special Topics in Optics and Photonics</i>” from 27th to 28th January - 2017 (2 Days) at RNSIT, Bengaluru. 		

- Someshvar s and Ohileshwari MS, “A Review on AMBA AHB-lite Protocol and verification using UVM Methodology” International Journal for Research in Applied Science & Engineering Technology (IJRASET) ISSN: 2321-9653; IC Value: 45.98; SJ Impact Factor: 7.429 Volume 9 Issue II Feb 2021. 2.
- Someshvar s and Ohileshwari MS, “Verification of AMBA AHB-lite Protocol using UVM Methodology” publication in Journal of Chengdu University of Technology (Science and Technology Edition), Present Scopus active, UGC-care(group-2) Approved journal, Volume 26, Issue 07, July-2021, In processing stage ID: CDU- 0721-18
- Ohileshwari M S, AnandaThirtha B Gudi,” IDDT-Based Fault Detection and Localization in 10-T Sub-Threshold SRAM Memory Array”, International Journal of Scientific Engineering and Research, October 2017, Volume 5 Issue 10, PP.51-57.
- Ohileshwari M S, AnandaThirtha B Gudi,” Stability Fault investigation in Subthreshold SRAM using Wavelet transform”, International Journal of VLSI Tools and Technology (VDDT), 2018

International conference:

- “Ohileshwari M S, AnandaThirtha B Gudi,” Detection of Stability Faults in Subthreshold SRAM cell Using IDDT Waveform”, Proceedings of the 2nd International Conference on Inventive Systems and Control (ICISC-2018), Coimbatore, INDIA , PP. 774 – 780, ISBN:978-1-5386-0807(Available in IEEE digital library).
 - Ohileshwari M S, AnandaThirtha B Gudi,” Performance Analysis of Ultra Low Power Single ended and Differential Sub-Threshold SRAM cells”, 2017 International Conference on Advanced Computing and Communication Systems (ICACCS -2017), Coimbatore, INDIA, PP.157-163, ISBN: 978-1-5090-4559.
1. Ohileshwari M S, Srinivasaiah H C, “Efficient Dynamic Current Testing Solution for Fault Masking in Memory Cells”, International Conference on Convergence of Technology (I2C2) – 2014, Pune,INDIA. ISBN: 978-1-4799-3759.
 2. Ohileshwari M S, Srinivasaiah H C, “Testing Analog Blocks Based on Terminal Characteristics of Highly Fault Sensitive Nodes”, International Conference on Convergence of Science, Engineering and Management in Research”, ICCSEM- 2013. National Conferences: